

Notice of References Cited	Application/Control No. 10/530,839		Applicant(s)/Patent Under Reexamination TERASHIMA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0116236 A1	06-2003	Hayakawa et al.	148/516
*	B	US-2001/0030001	10-2001	Hayakawa et al.	148/111
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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